

Notice of References Cited	Application/Control No.	Applicant(s)/Patent Under Reexamination WU ET AL.	
	Examiner Shean C Wu	Art Unit 1756	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5242618	09-1993	Krause et al.	252/299.6
	B	US-			
	C	US-			
	D	US-			
	E	US-			
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	J	US-			
	K	US-			
	L	US-			
	M	US-			

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	U	http://www6.ipdl.jpo.go.jp/Tokujitu/PAJdetail.ipdl?N0000=60&N0120=01&N2001=2&N3001=H10-045642 for English translation by Japan Patent Office
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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